

Search Notes

Application/Control No.

10/084,641

Examiner

Wesley D. Markham

Applicant(s)/Patent under
Reexamination

IKEDA ET AL.

Art Unit

1762

SEARCHED

Class	Subclass	Date	Examiner
427	162	10/13/2005	WM
	163.1		
	164		
	165		
	264		
	270		
	271		
	277		
	278		
	355		
	374.1		
	375		
	385.5		
	389.7		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
EAST search of US patent and PG pub claims		10/13/2005	WM

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor and assignee search	10/13/2005	WM
EAST search, all DBs (see search strategy printouts for details)		
Interference search terms: resin, curing, glass transition temperature, polymerize, stamp, emboss, pattern, microasperity,		
baking, alignment film, and variations and combinations thereof		

Search Notes (continued)

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SEARCHED

Class	Subclass	Date	Examiner
264	1.1	10/13/2005	WM
	1.31		
	1.34		
	1.7		
	1.9		
349	67		
	113		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR